

 <p>Substitute for form 1449/PTO</p> <p><b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b></p> <p>(Use as many sheets as necessary)</p>				<b>Complete if Known</b>	
				Application No.:	10/549,860
				Filing Date:	July 13, 2006
				First Named Inventor:	Nigel P. Smith
				Art Unit:	2811
				Examiner Name:	Ori Nadav
Sheet	1	of	1	Attorney Docket No.:	NAN155 US 8027

## U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Application of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear (if known)
		Number-Kind Code (if known)			
	1.	2001/0019401-A1	09-06-2001	Irie et al.	
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	3.	6,486,954-B1	11-26-2002	Mieher et al.	
	4.	6,982,793-B1	01-03-2006	Yang et al.	
	5.	7,230,705-B1	06-12-2007	Yang et al.	

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		Country Code Number Kind Code (if known)				
	6.	EP-0 534 720-A1, B1	03-31-1993	Levien		
	7.	EP-0 818 814-A2, A3	01-14-1998	KLA Instruments Corporation		
	8.	JP-11-191530-A	07-13-1999	Mitutoyo Corporation	Translation of Abstract	
	9.	WO-02/18871-A1	03-07-2002	KLA-Tencor Corporation		
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	11.	WO-2004/090978-A2, A3	10-21-2004	AOTI Operating Company, Inc.		
	12.	WO-2004/090979-A2, A3	10-21-2004	AOTI Operating Company, Inc.		

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
	13.	IBM Corp. (March 1990). "Interferometric Method of Checking the Overlay Accuracy in Photolitho-Graphic Exposure Processes," <i>IBM Technical Disclosure Bulletin</i> 32(10B):214-217.	
	14.	International Search Report mailed on October 8, 2004 for PCT Application No. PCT/GB2004/001536 filed on April 8, 2004 by AOTI Operating Company, Inc., 6 pages.	
	15.	International Preliminary Report on Patentability and Written Opinion mailed on October 14, 2005 for PCT Application No. PCT/GB2004/001536 filed on April 8, 2004 by AOTI Operating Company, Inc., 7 pages.	
	16.	Smith, Nigel P. et al. (August 1993). "Minimising Optical Overlay Measurement Errors," <i>Integrated Circuit Metrology, Inspection, and Process Control VII. Proceedings of SPIE</i> 1926:450-462.	

Examiner Signature:		Date Considered:	
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\* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.